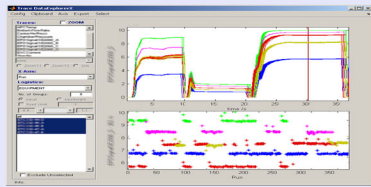
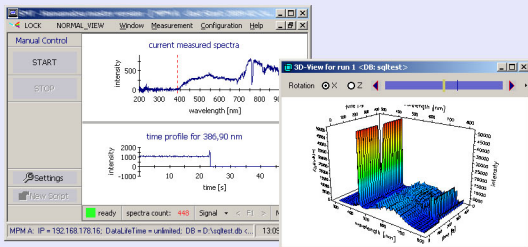


Services & Solutions

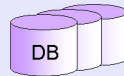
- ▶ consulting for data processing, signal analysis and modelling for APC and SPC



- ▶ control loop analysis and design, Run2Run batch processing control
- ▶ specification and development of complex software for offline and online applications using C++, VB and .NET

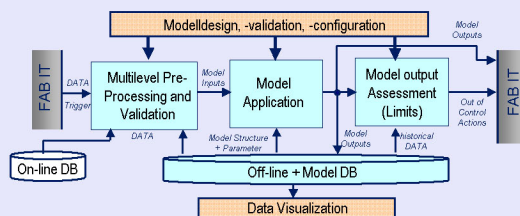


- ▶ database solutions for high volume data using Oracle, Access, MS SQL Server and SQLite



- ▶ rapid prototyping stand alone solutions using MATLAB / Java

- ▶ FRAMEWORK solutions



advanced data processing
GmbH
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Fax: +49 (0)351 20 44 99 1



advanced data processing
GmbH



... offers customized solutions for high volume data management, process modelling and control

- optimized data storage
- fast data acquisition
- exploratory visualization
- long term process monitoring
- data analysis & process modelling
- adaptive process control
- automated reporting

Eintrag im Handelsregister: Amtsgericht Dresden, HRB 18 805; USt-IdNr.: DE 210 673 793

Geschäftsführer: Dr.-Ing. Knut Voigtländer; Dipl. Ing. Jan Zimpel; Dipl. Ing. Jörn Kunze

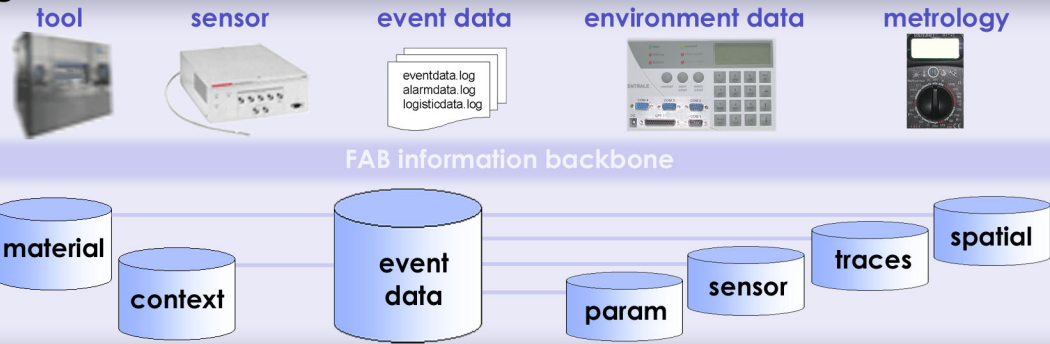
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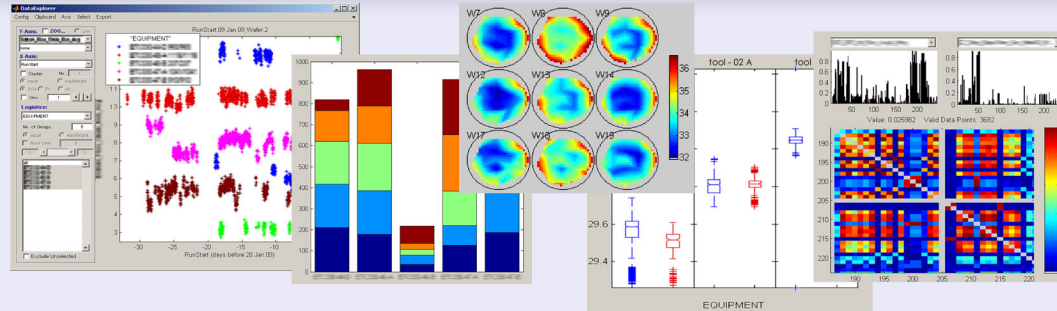
10 years experience with APC (advanced process control) and SPC (statistical process control) in semiconductor industries:

- ▶ design and operation of high volume database solutions for process-, sensor-, context- and event data storage
- ▶ fast and flexible processing, validation and visualization of large historical data sets
- ▶ enhanced exploratory and statistical data analysis for supervision, fault detection and virtual metrology
- ▶ context-dependent visualization of tool and metrology data, product parameters and yield
- ▶ high dimensional sensor data analysis (OES, NIR, Fluorescence) with multivariate methods (M-PCA, PCR, PLS, EFA) and FFT
- ▶ process modelling and adaptive parameterization
- ▶ model structure selection, optimization and validation, design of experiments
- ▶ batch process control (context sensitive feedforward and feedback loops)
- ▶ control loop benefit estimation based on historical process data

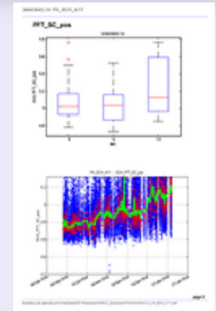
data management



data mining & visualization

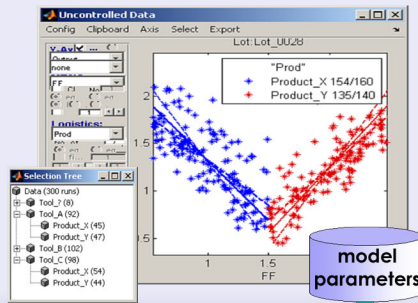


report generation

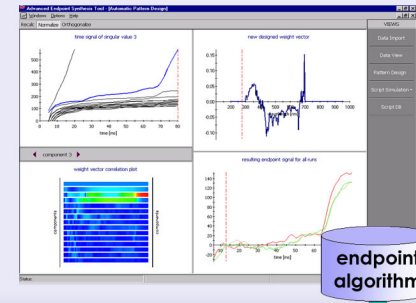


offline applications

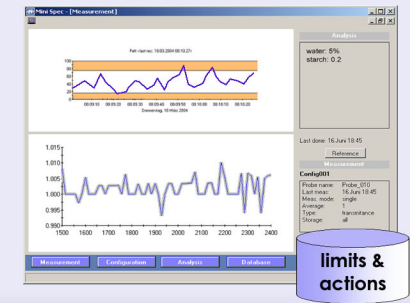
batch process modelling



process state estimation

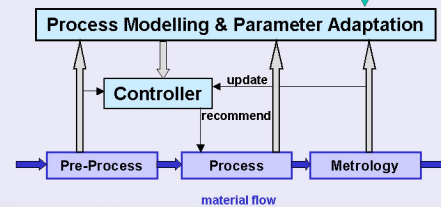


limit assessment

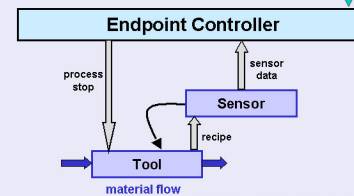


online

run-to-run control



in situ control



fault detection control

